

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74VCXR162500FT**LOW-VOLTAGE 18-BIT UNIVERSAL BUS TRANSCEIVER
WITH 3.6 V TOLERANT INPUTS AND OUTPUTS**

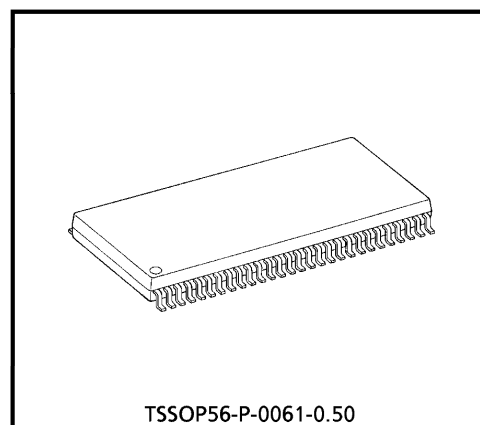
The TC74VCXR162500FT is a high performance CMOS 18-bit UNIVERSAL BUS TRANSCEIVER. Designed for use in 1.8, 2.5 or 3.3 Volt systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

It is also designed with over voltage tolerant inputs and outputs up to 3.6 V.

Data flow in each direction is controlled by output-enable ($\overline{OEAB}$ and $\overline{OEBA}$), latch-enable ($\overline{LEAB}$ and $\overline{LEBA}$), and clock ($\overline{CKAB}$ and $\overline{CKBA}$) inputs. For A-to-B data flow, the device operates in the transparent mode when $\overline{LEAB}$ is high. When $\overline{LEAB}$ is low, the A data is latched if $\overline{CKAB}$ is held at a high or low logic level. If $\overline{LEAB}$ is low, the A bus data is stored in the latch / flip-flop on the high-to-low transition of $\overline{CKAB}$.

Data flow for B to A is similar to that of A to B but uses $\overline{OEBA}$, $\overline{LEBA}$, and $\overline{CKBA}$. When the $\overline{OE}$ input is high, the outputs are in a high impedance state. This device is designed to be used with 3-state memory address drivers, etc.

The 26- Ω series resistor helps reducing output overshoot and undershoot without external resistor. All inputs are equipped with protection circuits against static discharge.



Weight : 0.25 g (Typ.)

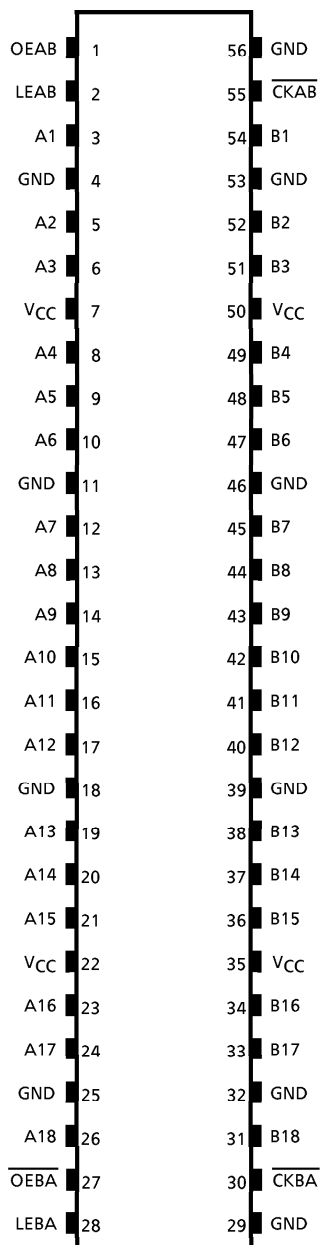
FEATURES

- 26- Ω Series Resistors on Outputs.
- Low Voltage Operation : $V_{CC} = 1.8 \sim 3.6 \text{ V}$
- High Speed Operation : $t_{pd} = 3.8 \text{ ns (max) at } V_{CC} = 3.0 \sim 3.6 \text{ V}$
 : $t_{pd} = 4.9 \text{ ns (max) at } V_{CC} = 2.3 \sim 2.7 \text{ V}$
 : $t_{pd} = 9.8 \text{ ns (max) at } V_{CC} = 1.8 \text{ V}$
- 3.6 V Tolerant inputs and outputs.
- Output Current : $I_{OH} / I_{OL} = \pm 12 \text{ mA (min) at } V_{CC} = 3.0 \text{ V}$
 : $I_{OH} / I_{OL} = \pm 8 \text{ mA (min) at } V_{CC} = 2.3 \text{ V}$
 : $I_{OH} / I_{OL} = \pm 4 \text{ mA (min) at } V_{CC} = 1.8 \text{ V}$
- Latch-up Performance : $\pm 300 \text{ mA}$
- ESD Performance : Human Body Model $> \pm 2000 \text{ V}$
 : Machine Model $> \pm 200 \text{ V}$
- Package : TSSOP (Thin Shrink Small Outline Package)
- Bidirectional interface between 2.5 V and 3.3 V signals.
- Power Down Protection is provided on all inputs and outputs.
- Supports live insertion / withdrawal (Note 3)

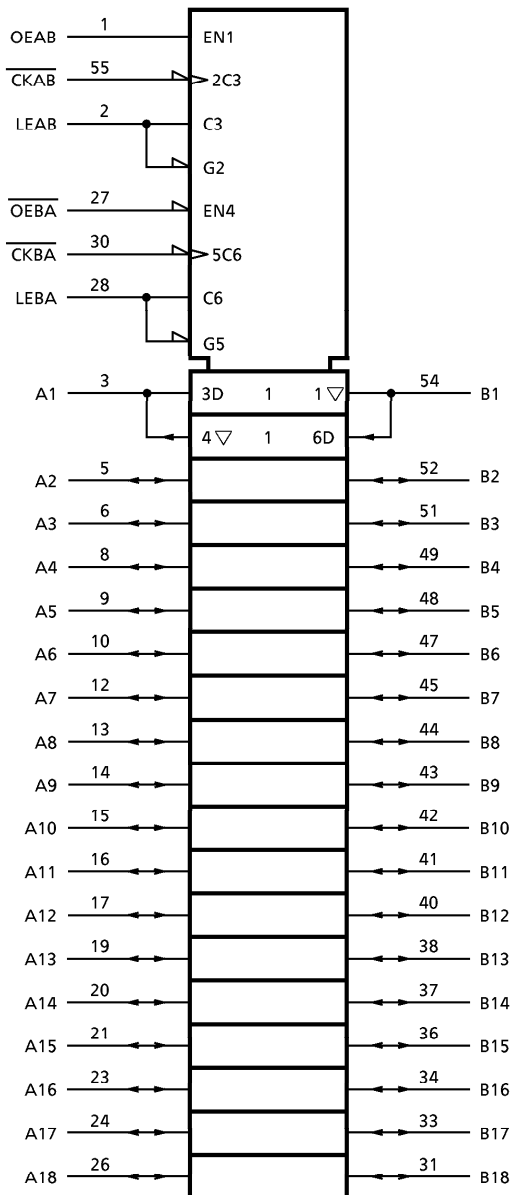
- (Note 1) : Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.
- (Note 2) : All floating (high impedance) bus terminal must have their input level fixed by means of pull up or pull down resistors.
- (Note 3) : To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

PIN ASSIGNMENT

SYMBOL



(TOP VIEW)

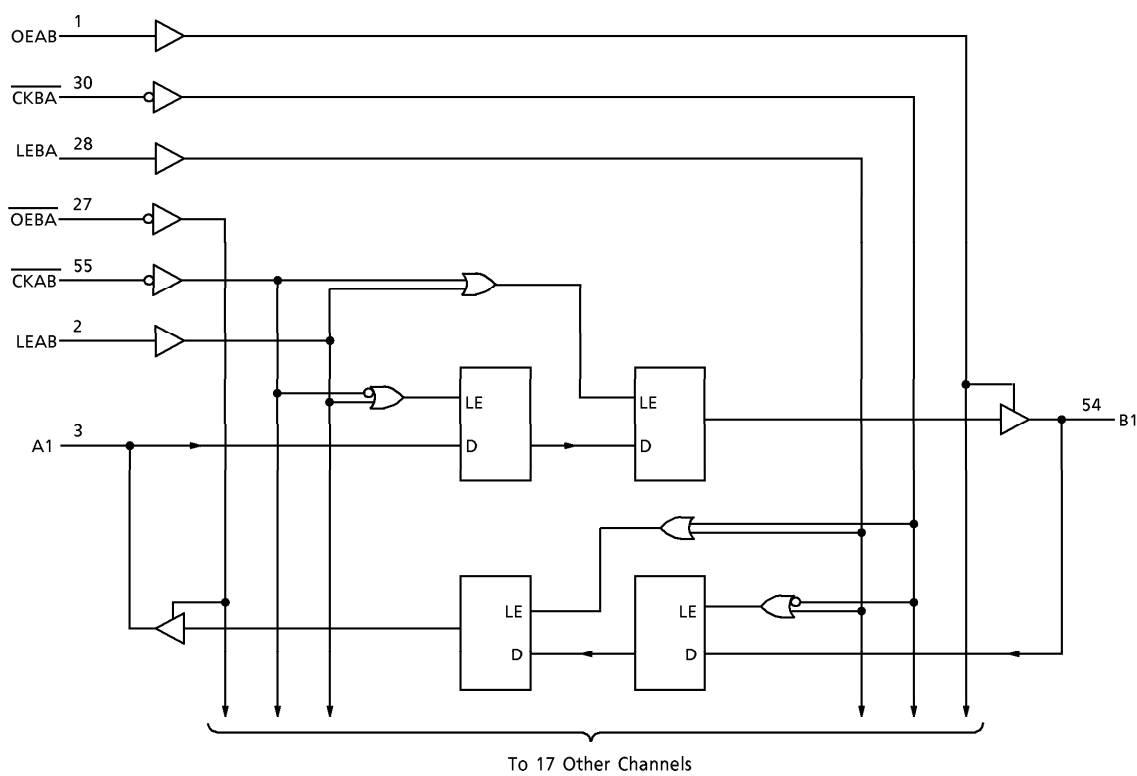


TRUTH TABLE *

INPUTS				OUTPUTS
OEAB	LEAB	CKAB	A	
L	X	X	X	Z
H	H	X	L	L
H	H	X	H	H
H	L		L	L
H	L		H	H
H	L	H	X	B0**
H	L	L	X	B0**

- * A-to-B data flow is shown: B-to-A flow is similar but uses $\overline{OEBA}$, $LEBA$, and $\overline{CKBA}$.
- ** Output level before the indicated steady-state input conditions were established, provided that $\overline{CKAB}$ was low or high before $LEAB$ went low.

SYSTEM DIAGRAM



MAXIMUM RATINGS

PARAMETER	SYMBOL	RATING	UNIT
Power Supply Voltage	V_{CC}	$-0.5 \sim 4.6$	V
DC Input Voltage (OEAB, $\overline{OEBA}$, LEAB, LEBA, $\overline{CKAB}$, $\overline{CKBA}$)	V_{IN}	$-0.5 \sim 4.6$	V
DC Bus I/O Voltage	$V_{I/O}$	$-0.5 \sim 4.6$ (Note 1)	V
		$-0.5 \sim V_{CC} + 0.5$ (Note 2)	
Input Diode Current	I_{IK}	-50	mA
Output Diode Current	I_{OK}	± 50 (Note 3)	mA
DC Output Current	I_{OUT}	± 50	mA
Power Dissipation	P_D	400	mW
DC V_{CC} / Ground Current Per Supply Pin	I_{CC} / I_{GND}	± 100	mA
Storage Temperature	T_{stg}	$-65 \sim 150$	$^{\circ}\text{C}$

(Note 1) : Off-State

(Note 2) : High or Low State. I_{OUT} absolute maximum rating must be observed.(Note 3) : $V_{OUT} < GND$, $V_{OUT} > V_{CC}$

RECOMMENDED OPERATING RANGE

PARAMETER	SYMBOL	RATING	UNIT
Supply Voltage	V_{CC}	1.8~3.6	V
		1.2~3.6 (Note 4)	
Input Voltage (OEAB, $\overline{OEBA}$, LEAB, LEBA, $\overline{CKAB}$, $\overline{CKBA}$)	V_{IN}	$-0.3 \sim 3.6$	V
Bus I/O Voltage	$V_{I/O}$	0~3.6 (Note 5)	V
		0~ V_{CC} (Note 6)	
Output Current	I_{OH} / I_{OL}	± 12 (Note 7)	mA
		± 8 (Note 8)	
		± 4 (Note 9)	
Operating Temperature	T_{opr}	$-40 \sim 85$	$^{\circ}\text{C}$
Input Rise And Fall Time	dt/dv	0~10 (Note 10)	ns / V

(Note 4) : Data Retention Only

(Note 5) : Off-State

(Note 6) : High or Low State

(Note 7) : $V_{CC} = 3.0 \sim 3.6$ V(Note 8) : $V_{CC} = 2.3 \sim 2.7$ V(Note 9) : $V_{CC} = 1.8$ V(Note 10) : $V_{IN} = 0.8 \sim 2.0$ V, $V_{CC} = 3.0$ V

ELECTRICAL CHARACTERISTICS

DC characteristics (Ta = -40~85°C, 2.7 V < V_{CC} ≤ 3.6 V)

PARAMETER		SYMBOL	TEST CONDITION		V _{CC} (V)	MIN	MAX	UNIT
Input Voltage	"H" Level	V _{IH}			2.7~3.6	2.0	—	V
	"L" Level	V _{IL}			2.7~3.6	—	0.8	
Output Voltage	"H" Level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = - 100 μA	2.7~3.6	V _{CC} - 0.2	—	V
				I _{OH} = - 6 mA	2.7	2.2	—	
				I _{OH} = - 8 mA	3.0	2.4	—	
				I _{OH} = - 12 mA	3.0	2.2	—	
	"L" Level	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	2.7~3.6	—	0.2	
				I _{OL} = 6 mA	2.7	—	0.4	
				I _{OL} = 8 mA	3.0	—	0.55	
				I _{OL} = 12 mA	3.0	—	0.8	
Input Leakage Current		I _{IN}	V _{IN} = 0~3.6 V	2.7~3.6	—	± 5.0	μA	
3-State Output Off-State Current		I _{OZ}	V _{IN} = V _{IH} or V _{IL} V _{OUT} = 0~3.6 V	2.7~3.6	—	± 10.0	μA	
Power Off Leakage Current		I _{OFF}	V _{IN} , V _{OUT} = 0~3.6 V	0	—	10.0	μA	
Quiescent Supply Current		I _{CC}	V _{IN} = V _{CC} or GND		2.7~3.6	—	20.0	μA
			V _{CC} ≤ (V _{IN} , V _{OUT}) ≤ 3.6 V		2.7~3.6	—	± 20.0	
Increase In I _{CC} Per Input		ΔI _{CC}	V _{IH} = V _{CC} - 0.6 V		2.7~3.6	—	750	μA

ELECTRICAL CHARACTERISTICS

DC characteristics (Ta = -40~85°C, 2.3 V ≤ V_{CC} ≤ 2.7 V)

PARAMETER		SYMBOL	TEST CONDITION			MIN	MAX	UNIT
			V _{CC} (V)					
Input Voltage	"H" Level	V _{IH}	2.3~2.7			1.6	—	V
	"L" Level	V _{IL}	2.3~2.7			—	0.7	
Output Voltage	"H" Level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = - 100 μA	2.3~2.7	V _{CC} - 0.2	—	V
				I _{OH} = - 4 mA	2.3	2.0	—	
				I _{OH} = - 6 mA	2.3	1.8	—	
				I _{OH} = - 8 mA	2.3	1.7	—	
	"L" Level	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	2.3~2.7	—	0.2	
				I _{OL} = 6 mA	2.3	—	0.4	
				I _{OL} = 8 mA	2.3	—	0.6	
Input Leakage Current		I _{IN}	V _{IN} = 0~3.6 V		2.3~2.7	—	± 5.0	μA
3-State Output Off-State Current		I _{OZ}	V _{IN} = V _{IH} or V _{IL} V _O _{UT} = 0~3.6 V		2.3~2.7	—	± 10.0	μA
Power Off Leakage Current		I _{OFF}	V _{IN} , V _O _{UT} = 0~3.6 V		0	—	10.0	μA
Quiescent Supply Current		I _{CC}	V _{IN} = V _{CC} or GND		2.3~2.7	—	20.0	μA
			V _{CC} ≤ (V _{IN} , V _O _{UT}) ≤ 3.6 V		2.3~2.7	—	± 20.0	

ELECTRICAL CHARACTERISTICS

DC characteristics ($T_a = -40 \sim 85^\circ\text{C}$, $1.8\text{ V} \leq V_{CC} < 2.3\text{ V}$)

PARAMETER		SYMBOL	TEST CONDITION		V _{CC} (V)	MIN	MAX	UNIT
Input Voltage	“H” Level	V _{IH}			1.8~2.3	0.7 × V _{CC}	—	V
	“L” Level	V _{IL}			1.8~2.3	—	0.2 × V _{CC}	
Output Voltage	“H” Level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = − 100 μA	1.8	V _{CC} − 0.2	—	V
				I _{OH} = − 4 mA	1.8	1.4	—	
	“L” Level	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	1.8	—	0.2	
				I _{OL} = 4 mA	1.8	—	0.3	
Input Leakage Current		I _{IN}	V _{IN} = 0~3.6 V		1.8	—	± 5.0	μA
3-State Output Off-State Current		I _{OZ}	V _{IN} = V _{IH} or V _{IL} V _{OUT} = 0~3.6 V		1.8	—	± 10.0	μA
Power Off Leakage Current		I _{OFF}	V _{IN} , V _{OUT} = 0~3.6 V		0	—	10.0	μA
Quiescent Supply Current		I _{CC}	V _{IN} = V _{CC} or GND		1.8	—	20.0	μA
			V _{CC} ≤ (V _{IN} , V _{OUT}) ≤ 3.6 V		1.8	—	± 20.0	

AC characteristics (Ta = -40~85°C, Input $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500 \Omega$)

PARAMETER	SYMBOL	TEST CONDITION	V _{CC} (V)	MIN	MAX	UNIT
Maximum Clock Frequency	f _{MAX}	(Fig.1, 3)	1.8	100	—	MHz
			2.5 ± 0.2	200	—	
			3.3 ± 0.3	250	—	
Propagation Delay Time (An, Bn-Bn, An)	t _{pLH} t _{pHL}	(Fig.1, 2)	1.8	1.5	9.8	ns
			2.5 ± 0.2	0.8	4.9	
			3.3 ± 0.3	0.6	3.8	
Propagation Delay Time ($\overline{\text{CKAB}}$, $\overline{\text{CLKBA}}$ -Bn, An)	t _{pLH} t _{pHL}	(Fig.1, 3)	1.8	1.5	9.8	ns
			2.5 ± 0.2	0.8	6.7	
			3.3 ± 0.3	0.6	5.1	
Propagation Delay Time (LEAB, LEBA-Bn, An)	t _{pLH} t _{pHL}	(Fig.1, 4)	1.8	1.5	9.8	ns
			2.5 ± 0.2	0.8	6.3	
			3.3 ± 0.3	0.6	4.7	
Output Enable Time (OEAB, $\overline{\text{OEBA}}$ -Bn, An)	t _{pZL} t _{pZH}	(Fig.1, 5, 6)	1.8	1.5	9.8	ns
			2.5 ± 0.2	0.8	5.9	
			3.3 ± 0.3	0.6	4.3	
Output Disable Time (OEAB, $\overline{\text{OEBA}}$ -Bn, An)	t _{pLZ} t _{pHZ}	(Fig.1, 5, 6)	1.8	1.5	8.8	ns
			2.5 ± 0.2	0.8	4.9	
			3.3 ± 0.3	0.6	4.3	
Minimum Pulse Width	t _w (H) t _w (L)	(Fig.1, 3, 4)	1.8	4.0	—	ns
			2.5 ± 0.2	1.5	—	
			3.3 ± 0.3	1.5	—	
Minimum Set-up Time	t _s	(Fig.1, 3, 4)	1.8	2.5	—	ns
			2.5 ± 0.2	1.5	—	
			3.3 ± 0.3	1.5	—	
Minimum Hold Time	t _h	(Fig.1, 3, 4)	1.8	1.0	—	ns
			2.5 ± 0.2	1.0	—	
			3.3 ± 0.3	1.0	—	
Output to Output Skew	t _{osLH} t _{osHL}	(Note 11)	1.8	—	0.5	ns
			2.5 ± 0.2	—	0.5	
			3.3 ± 0.3	—	0.5	

For $C_L = 50$ pF, add approximately 300 ps to the AC maximum specification.

(Note 11) : Parameter guaranteed by design.

($t_{osLH} = |t_{pLHm} - t_{pLHn}|$, $t_{osHL} = |t_{pHLm} - t_{pHLn}|$)

Dynamic switching characteristics (Ta = 25°C, Input $t_r = t_f = 2.0$ ns, $C_L = 30$ pF)

PARAMETER	SYMBOL	TEST CONDITION	V _{CC} (V)	TYP.	UNIT
Quiet Output Maximum Dynamic V _{OL}	V _{OLP}	V _{IH} = 1.8 V, V _{IL} = 0 V (Note 12)	1.8	0.15	V
		V _{IH} = 2.5 V, V _{IL} = 0 V (Note 12)	2.5	0.25	
		V _{IH} = 3.3 V, V _{IL} = 0 V (Note 12)	3.3	0.35	
Quiet Output Minimum Dynamic V _{OL}	V _{OLV}	V _{IH} = 1.8 V, V _{IL} = 0 V (Note 12)	1.8	-0.15	V
		V _{IH} = 2.5 V, V _{IL} = 0 V (Note 12)	2.5	-0.25	
		V _{IH} = 3.3 V, V _{IL} = 0 V (Note 12)	3.3	-0.35	
Quiet Output Minimum Dynamic V _{OH}	V _{OHV}	V _{IH} = 1.8 V, V _{IL} = 0 V (Note 12)	1.8	1.55	V
		V _{IH} = 2.5 V, V _{IL} = 0 V (Note 12)	2.5	2.05	
		V _{IH} = 3.3 V, V _{IL} = 0 V (Note 12)	3.3	2.65	

(Note 12) : Parameter guaranteed by design.

Capacitive characteristics (Ta = 25°C)

PARAMETER	SYMBOL	TEST CONDITION	V _{CC} (V)	TYP.	UNIT
Input Capacitance	C _{IN}	—	1.8, 2.5, 3.3	6	pF
Bus I/O Capacitance	C _{I/O}		1.8, 2.5, 3.3	7	pF
Power Dissipation Capacitance	C _{PD}	f _{IN} = 10 MHz (Note 13)	1.8, 2.5, 3.3	20	pF

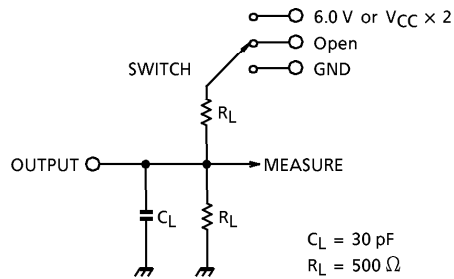
(Note 13) : C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

$$I_{CC}(\text{opr.}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 18 (\text{per bit})$$

TEST CIRCUIT

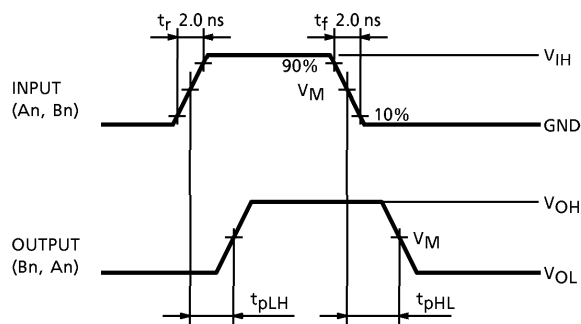
Fig.1



PARAMETER	SWITCH
t_{pLH} , t_{pHL}	Open
t_{pLZ} , t_{pZL}	6.0 V @ $V_{CC} = 3.3 \pm 0.3$ V $V_{CC} \times 2$ @ $V_{CC} = 2.5 \pm 0.2$ V @ $V_{CC} = 1.8$ V
t_{pHZ} , t_{pZH}	GND

AC WAVEFORM

Fig.2 t_{pLH} , t_{pHL}



SYMBOL	V _{CC}		
	3.3 ± 0.3 V	2.5 ± 0.2 V	1.8 V
V _{IH}	2.7 V	V _{CC}	V _{CC}
V _M	1.5 V	V _{CC} / 2	V _{CC} / 2
V _X	V _{OL} + 0.3 V	V _{OL} + 0.15 V	V _{OL} + 0.15 V
V _Y	V _{OH} - 0.3 V	V _{OH} - 0.15 V	V _{OH} - 0.15 V

Fig.3 t_{pLH} , t_{pHL} , t_w , t_s , t_h

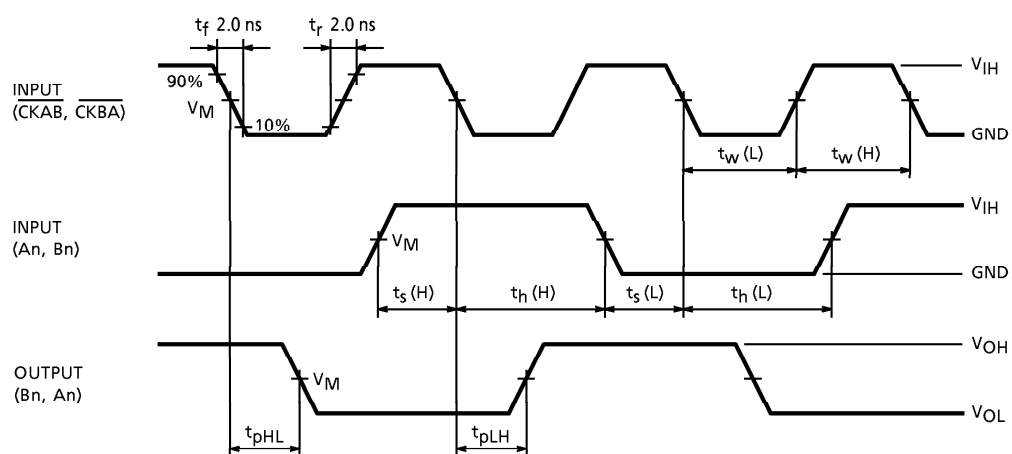
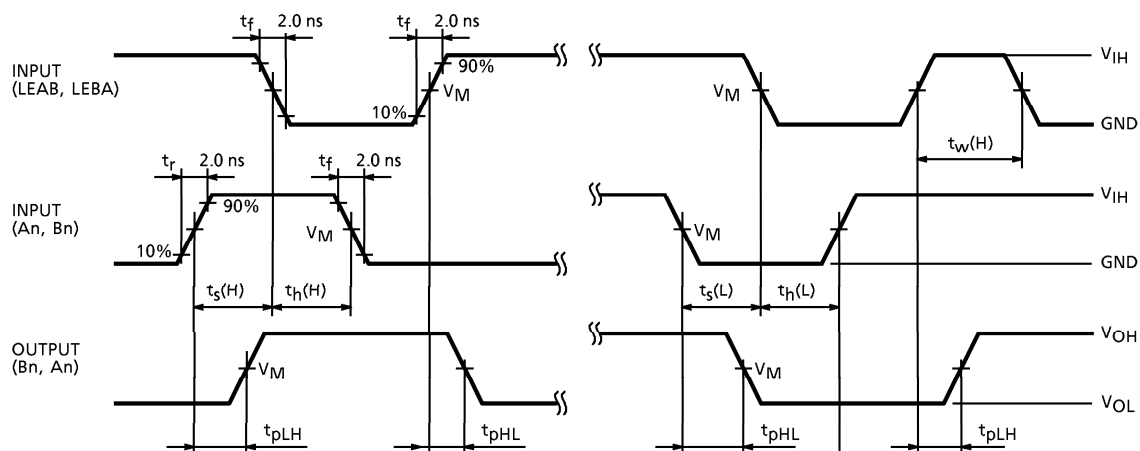
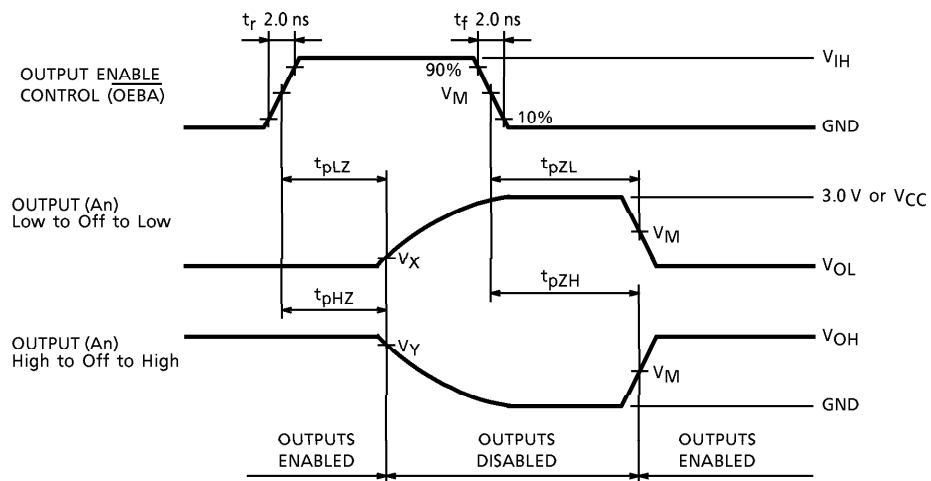
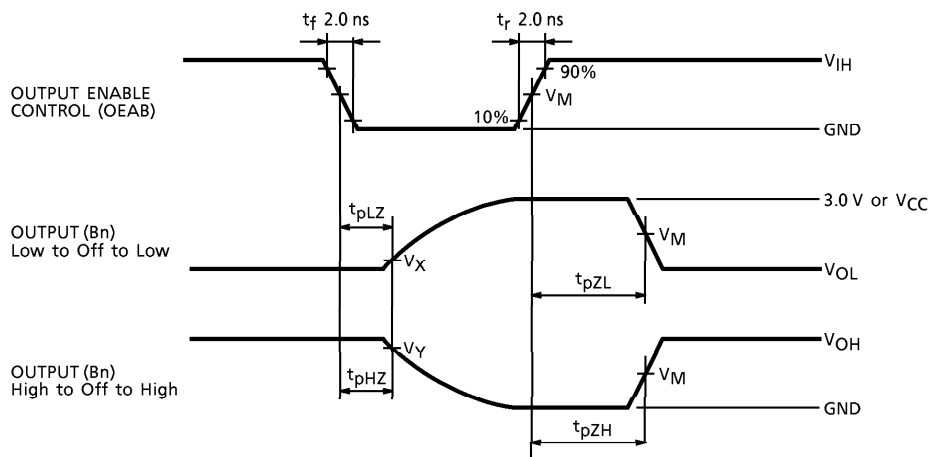
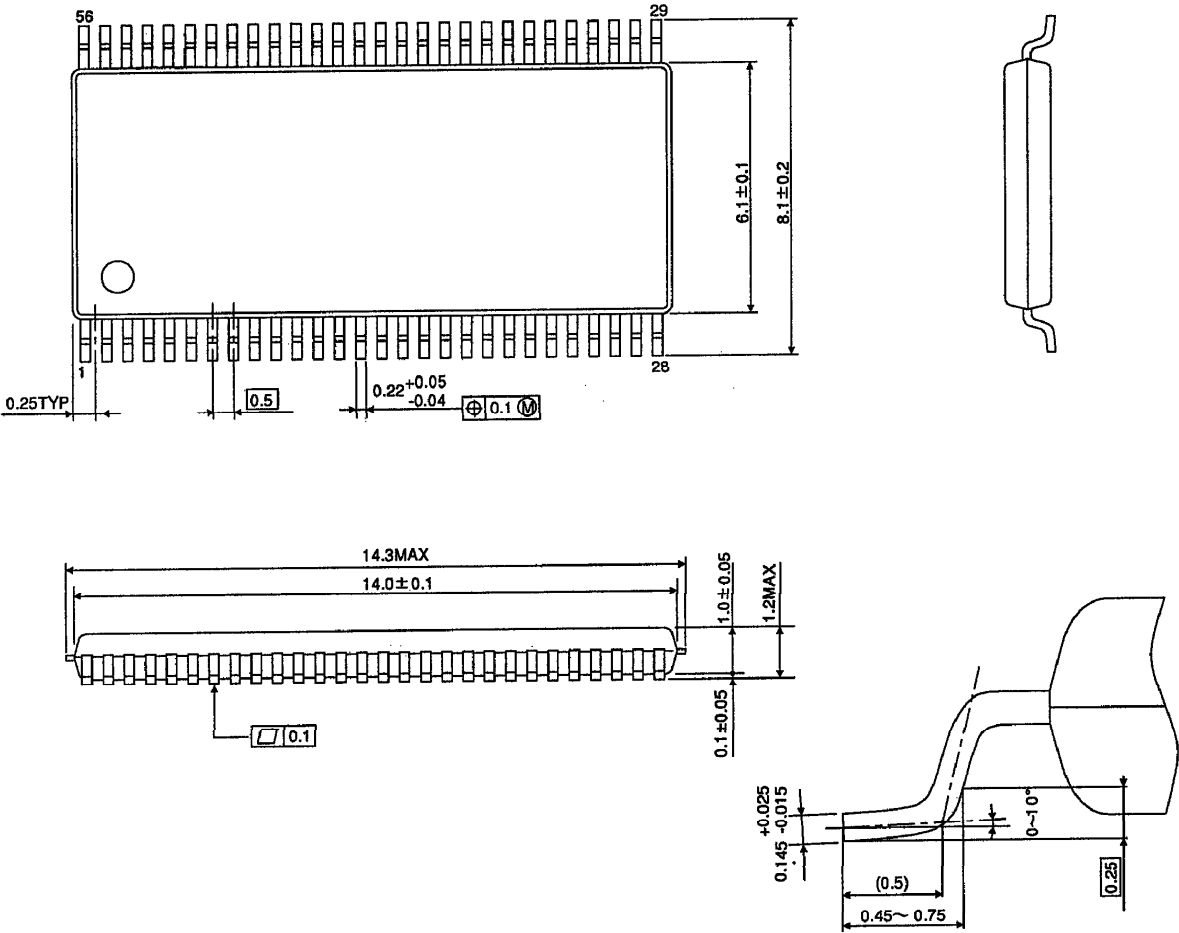


Fig.4 t_{pLH} , t_{pHL} , t_w , t_s , t_h Fig.5 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH} Fig.6 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH} 

PACKAGE DIMENSIONS
TSSOP56-P-0061-0.50

Unit : mm



Weight : 0.25 g (Typ.)

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000707EBA

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